

Notice of References Cited	Application/Control No. 10/615,403		Applicant(s)/Patent Under Reexamination ONOE ET AL.	
	Examiner Kevin M. Bernatz		Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,242,661	07-2007	Cho et al.	369/126
*	B	US-5,481,527	01-1996	Kasanuki et al.	369/126
*	C	US-7,020,064	03-2006	Kim et al.	369/126
*	D	US-6,850,480	02-2005	Naito et al.	369/288
*	E	US-5,226,029	07-1993	Takanashi et al.	369/100
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Derwent Abstract Translation of EP 1091355 A2 (Derwent Acc-No: 2001-542921).
	V	Derwent Abstract Translation of EP 398656 A (Derwent Acc-No: 1990-350392).
	W	Derwent Abstract Translation of EP 1154422 A2 (Derwent Acc-No: 2002-229459).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.